

# FILL THE VOID IV: ELIMINATION OF INTER-VIA VOIDING

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# OUTLINE

- Introduction
- Factors that Influence Voiding
- Methodology
- Voiding Results
- Recommendations to Fill the Void
- Future Work
- Acknowledgements
- Thank You & Questions





# INTRODUCTION



## **INTRODUCTION ON VOIDING**



Voiding is Common for QFN Thermal Pads with Via Holes

## FACTORS THAT INFLUENCE VOIDING FOR VIA-IN-PAD DESIGNS

SUCCEED VELOCITY

TECHNOLOGY

AT THE



### Via Hole Plugging Options: Open, S/M Tent, Plugged

## FACTORS THAT INFLUENCE VOIDING FOR VIA-IN-PAD DESIGNS

SUCCEED VELDEITY

TECHNOLOGY

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# METHODOLOGY



### **METHODOLOGY – CIRCUIT BOARDS**

SUCCEED VELOCITY AT THE

TECHNOLOGY



PR Test Board with Via in Pad (0.3 mm = 12 mil vias), Plated with ENIG

### **METHODOLOGY – CIRCUIT BOARDS**

SUCCEED VELOCITY AT THE

OF

TECHNOLOGY



PR Test Board with a Solder Mask Tent on the Bottom Side

### **METHODOLOGY – CIRCUIT BOARDS**

SUCCEED VELOCITY AT THE

TECHNOLOGY



PR Test Board with Non-Conductive Via Fill, Plated with Cu and ENIG

### **METHODOLOGY – QFN COMPONENTS**

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QFN Components: 10 mm body (68 lead) and 7 mm body (48 lead). Matte Tin Finish

### **METHODOLOGY – STANDARD STENCIL**

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Standard Solder Paste Print: 65% Area Window Pane. Printed Over Via Holes

### **METHODOLOGY – MODIFIED STENCIL**

SUCCEED VELDEITY

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Modified Solder Paste Print: 63% Area Grid. Printed Around Via Holes

### **METHODOLOGY – SOLDER PASTE AND REFLOW**

SUCCEED VELOCITY AT THE

TECHNOLOGY

No Clean SAC305 Type 3 Solder Paste



Setting	<b>RTS Profile</b>
Ramp rate	1.7 – 1.8 °C/sec
Reflow Time (> 220 °C)	61 - 67  sec
Peak temperature	241 to 248 °C
Profile length (25 °C to peak)	4.70 minutes

# **METHODOLOGY – EXPERIMENTAL PROCEDURE**

10 Circuit Boards For Each Variation

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- 4 of Each QFN Size Placed and Boards were Reflowed
- Void Area and Largest Size Measured on Each QFN
- Images were Taken of Representative QFN Voiding
- Data was Analyzed and Statistics Generated

ELOCITY





# **VOIDING RESULTS**



### **VOIDING RESULTS – VIA FILL OPTIONS, STANDARD STENCIL**

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	Open Vias	Solder Mask Tent	Complete Plug	Flat Thermal Pad
	(No Fill)			(No Via)
QFN7				
QFN10			0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0         0       0       0       0       0       0       0       0       0	

3D Voiding Images: Open Vias = Lower Voiding, Plugged and No Vias = More Voiding

## **VOIDING RESULTS – VIA FILL OPTIONS, MODIFIED STENCIL**

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	Open Vias (No Fill)	Solder Mask Tent	Complete Plug
QFN7			
QFN10			

3D Voiding Images: Open Vias = Lower Voiding, Plugged Vias = More Voiding

### **VOIDING SIZE – BY STENCIL**

TECHNOLOGY

SUCCEED VELDEITY



Excluded Rows 400

#### Means Comparisons

AT THE

Comparisons for all pairs using Tukey-Kramer HSD

#### **Connecting Letters Report**

Level		Mean	
PR Plug	A	3.8162500	
PR	В	2.5537500	
PR Tent	С	0.5500000	
PR Via	С	0.4762500	
Levels no	t connected	l by same letter a	are significantly different.

STANDARD STENCIL



Excluded Rows 480

#### Means Comparisons

Comparisons for all pairs using Tukey-Kramer HSD

#### **Connecting Letters Report**

Level		Mean	
PR Plug A	۸	3.4425000	
PR Tent	в	0.6375000	
PR Via	в	0.5575000	
Levels not	conne	ected by same letter a	re significantly different.

### **MODIFIED STENCIL**

PR = Flat Pad (No Vias) PR Plug = Plugged Vias PR Tent = S/M Tented Vias PR Via = Open Vias

### SOLDER FLOW TO THE BOTTOM OF THE BOARD



### STANDARD STENCIL

SUCCEED VELOCITY AT THE

TECHNOLOGY

### **MODIFIED STENCIL**

## **VOIDING SIZE BY STENCIL DESIGN FOR EACH VIA TYPE**



SUCCEED VELOCITY AT THE

TECHNOLOGY

Level		Mean	
PRV	А	0.55750000	
CH65	А	0.47625000	
Levels	not	connected by same letter	are significantly different.





Compariso	ns for all pairs using Tukey-Kramer HSD
Connecti	ng Letters Report
Level	Mean
Level PRV A	Mean 0.63750000



ompariso	ns for all pairs using Tukey-Kramer HSD
Connecti	ng Letters Report
Level	Mean
CH65 A	3.8162500
PRV A	3.4425000

Levels not connected by same letter are significantly different.

### **TENTED VIAS**

### PLUGGED VIAS

## **VOIDING BY QFN SIZE**

SUCCEED VELOCITY

TECHNOLOGY



Excluded Rows 160

#### Means Comparisons

AT THE

Comparisons for all pairs using Tukey-Kramer HSD

#### **Connecting Letters Report**

 Level
 Mean

 QFN7
 A
 2.2310714

 QFN10
 B
 1.2071429

 Levels not connected by same letter are significantly different.

### LARGEST VOID SIZE



Excluded Rows 640

Means Comparisons

Comparisons for all pairs using Tukey-Kramer HSD

Connecting Letters Report

 Level
 Mean

 QFN7
 A
 10.130000

 QFN10
 B
 7.995000

 Levels not connected by same letter are significantly different.

### **VOID AREA**

Standard Stencil (65%) Flat QFN Pads – No Vias QFN10 Mass = 2x QFN7



# FILL THE VOID



# **RECOMMENDATIONS TO FILL THE VOID**

- Void size can be reduced using via holes in QFN thermal pads.
- Modifications to the stencil design limits the amount of solder flow through the via holes.
- Use of larger QFN's may reduce overall voiding.

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ELOCITY

### Via holes in QFN thermal pads certainly influence voiding!



# **FUTURE WORK**

Work on mitigation strategies to reduce voiding is ongoing. Data will be presented at future technical conferences.





## ACKNOWLEDGEMENTS

Greg Smith with BlueRing Stencils designed and supplied the stencils used in this work.



